

**SLOVENSKI STANDARD**  
**oSIST prEN IEC 61326-2-7:2026**  
**01-junij-2026**

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**Električna oprema za merjenje, nadzor in laboratorijsko uporabo - Zahteve za elektromagnetno združljivost (EMC) - 2-7. del: Posebne zahteve - Preskusne konfiguracije, obratovalni pogoji, preskusne ravni in merila zmogljivosti za naprave z Ethernet-APL vmesniki**

Electrical equipment for measurement, control and laboratory use - EMC requirements - Part 2-7: Particular requirements - Test configurations, operational conditions, test levels and performance criteria for devices with Ethernet-APL interfaces (IEC 61326-2-7:2025)

Elektrische Mess-, Steuer-, Regel- und Laborgeräte - EMV-Anforderungen - Teil 2-7: Besondere Anforderungen - Prüfkonfigurationen, Betriebsbedingungen, Prüfstufen und Leistungskriterien für Geräte mit Ethernet-APL-Schnittstellen (IEC 61326-2-7:2025)

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**Ta slovenski standard je istoveten z: prEN IEC 61326-2-7:2026**

**ICS:**

19.080	Električno in elektronsko preskušanje	Electrical and electronic testing
25.040.40	Merjenje in krmiljenje industrijskih postopkov	Industrial process measurement and control
33.100.01	Elektromagnetna združljivost na splošno	Electromagnetic compatibility in general

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**en,fr,de**

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EUROPEAN STANDARD  
NORME EUROPÉENNE  
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**DRAFT**  
**prEN IEC 61326-2-7**

April 2026

ICS 17.220.20; 25.040.40; 33.100.20

English Version

Electrical equipment for measurement, control and laboratory use - EMC requirements - Part 2-7: Particular requirements - Test configurations, operational conditions, test levels and performance criteria for devices with Ethernet-APL interfaces  
(IEC 61326-2-7:2025)

To be completed  
(IEC 61326-2-7:2025)

Elektrische Mess-, Steuer-, Regel- und Laborgeräte - EMV-Anforderungen - Teil 2-7: Besondere Anforderungen - Prüfkonfigurationen, Betriebsbedingungen, Prüfstufen und Leistungskriterien für Geräte mit Ethernet-APL-Schnittstellen  
(IEC 61326-2-7:2025)

This draft European Standard is submitted to CENELEC members for enquiry.  
Deadline for CENELEC: 2026-07-17.

The text of this draft consists of the text of IEC 61326-2-7:2025.

If this draft becomes a European Standard, CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

This draft European Standard was established by CENELEC in three official versions (English, French, German).  
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Recipients of this draft are invited to submit, with their comments, notification of any relevant patent rights of which they are aware and to provide supporting documentation.

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**CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels**

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Ref. No. prEN IEC 61326-2-7:2026 E

## prEN IEC 61326-2-7:2026 (E)

### European foreword

This document (prEN IEC 61326-2-7:2026) consists of the text of IEC 61326-2-7:2025 prepared by IEC/TC 65 "Industrial-process measurement, control and automation".

This document is currently submitted to the Enquiry.

The following dates are proposed:

- latest date by which the existence of this document (doa)      dav + 6 months  
has to be announced at national level
- latest date by which this document has to be (dop)      dav + 12 months  
implemented at national level by publication of an  
identical national standard or by endorsement
- latest date by which the national standards (dow)      dav + 36 months  
conflicting with this document have to be withdrawn      (to be confirmed or  
modified when voting)

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## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: [www.cencenelec.eu](http://www.cencenelec.eu).

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-161	1990	International Electrotechnical Vocabulary. Chapter 161: Electromagnetic compatibility	-	-
IEC 61000-3-2	-	Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current $\leq 16$ A per phase)	EN IEC 61000-3-2	-
IEC 61000-3-3	-	Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current $\leq 16$ A per phase and not subject to conditional connection	EN 61000-3-3	-
IEC 61000-3-11	-	Electromagnetic compatibility (EMC) - Part 3-11: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems - Equipment with rated current $\leq 75$ A and subject to conditional connection	EN IEC 61000-3-11	-
IEC 61000-3-12	-	Electromagnetic compatibility (EMC) - Part 3-12: Limits - Limits for harmonic currents produced by equipment connected to public low-voltage systems with input current $> 16$ A and $\leq 75$ A per phase	EN 61000-3-12	-
IEC 61000-4-2	2025	Electromagnetic compatibility (EMC) - Part 4-2: Testing and measurement techniques - Electrostatic discharge immunity test	EN IEC 61000-4-2	2025
IEC 61000-4-3	2020	Electromagnetic compatibility (EMC) - Part 4-3 : Testing and measurement techniques - Radiated, radio-frequency, electromagnetic field immunity test	EN IEC 61000-4-3	2020
IEC 61000-4-4	2012	Electromagnetic compatibility (EMC) - Part 4-4: Testing and measurement techniques - Electrical fast transient/burst immunity test	EN 61000-4-4	2012

**prEN IEC 61326-2-7:2026 (E)**

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61000-4-5	2014	Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test	EN 61000-4-5	2014
IEC 61000-4-6	2023	Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields	EN IEC 61000-4-6	2023
IEC 61000-4-8	2009	Electromagnetic compatibility (EMC) - Part 4-8: Testing and measurement techniques - Power frequency magnetic field immunity test	EN 61000-4-8	2010
IEC 61000-4-11	2020	Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current up to 16 A per phase	EN IEC 61000-4-11	2020
IEC 61000-4-16	2015	Electromagnetic compatibility (EMC) - Part 4-16: Testing and measurement techniques - Test for immunity to conducted, common mode disturbances in the frequency range 0 Hz to 150 kHz	EN 61000-4-16	2016
IEC 61000-4-29	2000	Electromagnetic compatibility (EMC) - Part 4-29: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests	EN 61000-4-29	2000
IEC 61326-1	2020	Electrical equipment for measurement, control and laboratory use - EMC requirements - Part 1: General requirements	EN IEC 61326-1	2021
IEC/TS 63444	2023	Industrial networks - Ethernet-APL port profile specification	-	-
CISPR 11	2024	Industrial, scientific and medical equipment - Radio-frequency disturbance characteristics - Limits and methods of measurement	EN IEC 55011	2025
IEEE 802.3	2022	IEEE Standard for Ethernet	-	-



IEC 61326-2-7

Edition 1.0 2025-12

# INTERNATIONAL STANDARD

**Electrical equipment for measurement, control and laboratory use - EMC requirements -  
Part 2-7: Particular requirements - Test configurations, operational conditions, test levels and performance criteria for devices with Ethernet-APL interfaces**

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**Electrical equipment for measurement, control and laboratory use -  
EMC requirements -  
Part 2-7: Particular requirements - Test configurations, operational  
conditions, test levels and performance criteria  
for devices with Ethernet-APL interfaces**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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IEC 61326-2-7 has been prepared by subcommittee 65A: System aspects, of IEC technical committee 65: Industrial-process measurement, control and automation. It is an International Standard.

The text of this International Standard is based on the following documents:

Draft	Report on voting
65A/1190/FDIS	65A/1196/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

## IEC 61326-2-7:2025 © IEC 2025

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at [www.iec.ch/members\\_experts/refdocs](http://www.iec.ch/members_experts/refdocs). The main document types developed by IEC are described in greater detail at [www.iec.ch/publications](http://www.iec.ch/publications).

Words in SMALL CAPITALS in the text are defined in Clause 3.

A list of all parts of the IEC 61326 series, under the general title *Electrical equipment for measurement, control and laboratory use - EMC requirements*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under [webstore.iec.ch](http://webstore.iec.ch) in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn, or
- revised.

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## 1 Scope

In addition to the requirements of IEC 61326-1, this part of IEC 61326 specifies the EMC test requirements for process automation equipment using at least one Ethernet-APL (Ethernet ADVANCED PHYSICAL LAYER) compliant port according IEC TS 63444. The type of equipment covered by this document includes INFRASTRUCTURE DEVICES such as switches as well as measurement and control devices. This document provides requirements for the EMC test setups of the APL interface for devices intended for use in process control and process measurement.

The other functions of the equipment remain covered by other parts of the IEC 61326 series.

NOTE Ethernet-APL uses IEEE Std. 802.3-2022 Ethernet Physical Layer 10BASE-T1L, suitable to be used for full-duplex communication over a single balanced pair of conductors.

The test levels are based on the intended environment as stated in the product's specification or user documentation and selected appropriately from IEC 61326-1.

## 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, *International Electrotechnical Vocabulary (IEV) - Part 161: Electromagnetic compatibility*

IEC 61000-3-2, *Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current  $\leq 16$  A per phase)*

IEC 61000-3-3, *Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current  $\leq 16$  A per phase and not subject to conditional connection*

IEC 61000-3-11, *Electromagnetic compatibility (EMC) - Part 3-11: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems - Equipment with rated current  $\leq 75$  A and subject to conditional connection*

IEC 61000-3-12, *Electromagnetic compatibility (EMC) - Part 3-12: Limits - Limits for harmonic currents produced by equipment connected to public low-voltage systems with input current  $> 16$  A and  $\leq 75$  A per phase*

IEC 61000-4-2:2025, *Electromagnetic compatibility (EMC) - Part 4-2: Testing and measurement techniques - Electrostatic discharge immunity test*

IEC 61000-4-3:2020, *Electromagnetic compatibility (EMC) - Part 4-3: Testing and measurement techniques - Radiated, radio-frequency, electromagnetic field immunity test*

IEC 61000-4-4:2012, *Electromagnetic compatibility (EMC) - Part 4-4: Testing and measurement techniques - Electrical fast transient/burst immunity test*

IEC 61000-4-5:2014, *Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test*

IEC 61000-4-6:2023, *Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields*